

<b>Notice of References Cited</b>	Application/Control No. 10/786,261	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0141698	10-2002	Matsushita et al.	385/31
	B	US-2002/0101634	08-2002	Ye, Feng	359/122
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	NONE				
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#### NON-PATENT DOCUMENTS

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	U	NONE
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